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By: STACY R. BAKER-COLE Signed: Stacy R Baker-Cole

Date of signature and deposit/transmission: January 25, 2004

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of: Victor W. Lowe, Jr. et al.) Group Art Unit:
Serial No.: 10/669,907) Examiner:
Filed: September 24, 2003) Attorney Docket: 200-0252
For: METHOD FOR ANALYZING)
WARRANTLY CLAIM DATA)

Commissioner for Patents
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INFORMATION DISCLOSURE STATEMENT

Honorable Sir:

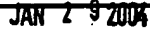
Pursuant to 37 C.F.R. 1.97(b), record is hereby made of information, which the Patent Office may wish to consider in connection with its examination of the above-identified application.

Pursuant to the Waiver of 37 C.F.R. 1.98(a)(2)(i), copies of any cited U.S. patents or U.S. published applications are not attached. Copies are attached for any foreign or non-patent literature cited on the attached PTO-1449 form.

Respectfully submitted,

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SERIAL NO.

200-0252

10/669,907

APPLICANT

VICTOR W. LOWE, JR. ET AL.

FILING DATE

GROUP

SEPTEMBER 24, 2003

[illegible][illegible]

		Devore, Jay L. Probability and Statistics for Engineering and the Sciences Fourth Edition, Duxberry Press, 1995, pp. 658-660
		Wu et al, Early Detection of Reliability Problems Using Information from Warranty Databases, Technometrics, May 2002, Vol. 44, No. 2, pp. 120-133
		Montgomery, D.C., Introduction to Statistical Quality Control, Chapter 4 - Methods and Philosophy of Statistical Process Control, John Wiley & Sons, 1997 pp. 153-177
		Montgomery, D.C., Introduction to Statistical Quality Control, Chapter 6 - Control Charts and Attributes, John Wiley & Sons, 1997 pp. 283-303

DATE CONSIDERED

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.